

Notice of References Cited	Application/Control No. 10/788,899		Applicant(s)/Patent Under Reexamination TOREK, K ET AL	
	Examiner Anita K. Alanko		Art Unit 1765	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0175884 A1	09-2004	Kang et al.	438/254
*	B	US-5,817,182 A	10-1998	O'Brien, Sean C.	134/1.3
*	C	US-5,966,611 A	10-1999	Jost et al.	438/397
*	D	US-2004/0018679 A1	01-2004	Yu et al.	438/253
*	E	US-2002/0127795 A1	09-2002	Shih, Pen-Chen	438/243
*	F	US-2002/0163026 A1	11-2002	Park, Hong-Bae	257/301
*	G	US-6,825,121 B2	11-2004	Kwean et al.	438/694
*	H	US-6,830,979 B2	12-2004	Wada, Yukihisa	438/303
*	I	US-5,496,757 A	03-1996	Rosner, Wolfgang	438/253
*	J	US-5,168,073 A	12-1992	Gonzalez et al.	438/397
*	K	US-5,770,510 A	06-1998	Lin et al.	438/396
*	L	US-6,559,498 B2	05-2003	Kitamura, Hiroyuki	257/309
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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